Notice of References Cited Application/Control No. 10/627,962 Examiner Siu M. Lee Applicant(s)/Patent Under Reexamination PIIRAINEN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,568,519	10-1996	Baier et al.	375/343
*	В	US-2001/0014114 a1	08-2001	Baltersee et al.	375/148
*	С	US-2002/0101936 a1	08-2002	Wright et al.	375/296
*	D	US-6,504,862 b1	01-2003	Yang, Hong-Kui	375/146
*	Е	US-7,054,385 b2	05-2006	Booth et al.	375/300
*	F	US-5,638,403	06-1997	Birchler et al.	375/296
*	G	US-2003/0086507 a1	05-2003	Kim et al.	375/297
*	Η	US-2003/0054851 a1	03-2003	Jo et al.	455/522
*	ı	US-6,687,511 b2	02-2004	McGowan et al.	455/522
*	J	US-6,392,483 b2	05-2002	Suzuki et al.	330/151
*	К	US-6,366,619 b1	04-2002	McCallister et al.	375/295
*	L	US-2001/0006359 a1	07-2001	Suzuki et al.	333/14
*	М	US-2004/0203430 a1	10-2004	Morris, Bradley John	455/067.11

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Ρ					
	α					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
	ŵ	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.